Hybrid 8j129 Traveler

May 31, 2000

1 Connectivity

Repairs on shorts:
Fixes for opens:

2 Chips

The following chips were assembled on this hybrid (in the order that the chips get read out):
Hybrid 8J129 has die: 196-011 196-014 196-015 196-018 198-117 198-119 198-121 198-123

3 Data Analysis Summary

The following summarizes the findings of the Burn-in data analysis program. The first chip in the readout name is numbered 0.

```
% Hybrid 8j129 classification info. Created 14:44:29 05/29/00

Hybrid 8j129 quality: fair
Chip classification: fair fair good good good good good fair
Bad channels (chip-channel): 0-37 1-36 1-64 7-109
Bad cells: none
Random bad capacitors (chip-cell-channel): 0-1-26 1-31-7 7-0-110
   7-16-110 7-3-110 7-38-111 7-41-110 7-45-110 7-5-110 7-6-110 7-7-110
Channels at pedestal needed for DCMS: 30.6 30.9 32.6 31.6 32.6 35.6 33.6 32.6
```

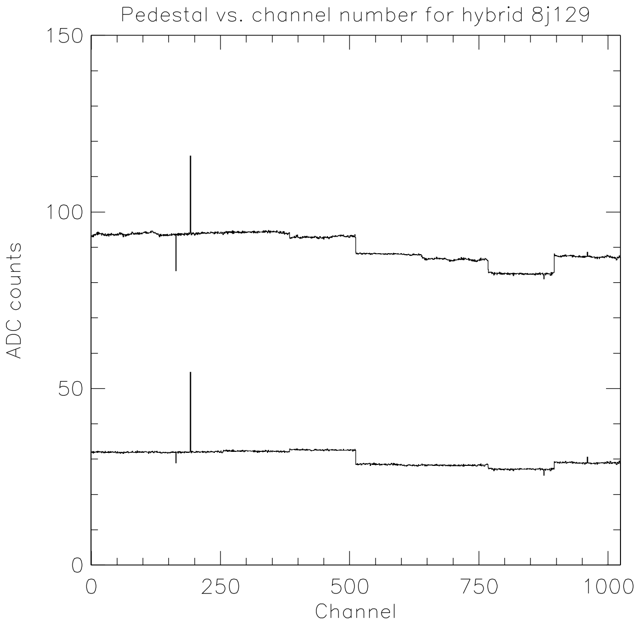
4 Comments

HV tested.

5 Pedestal

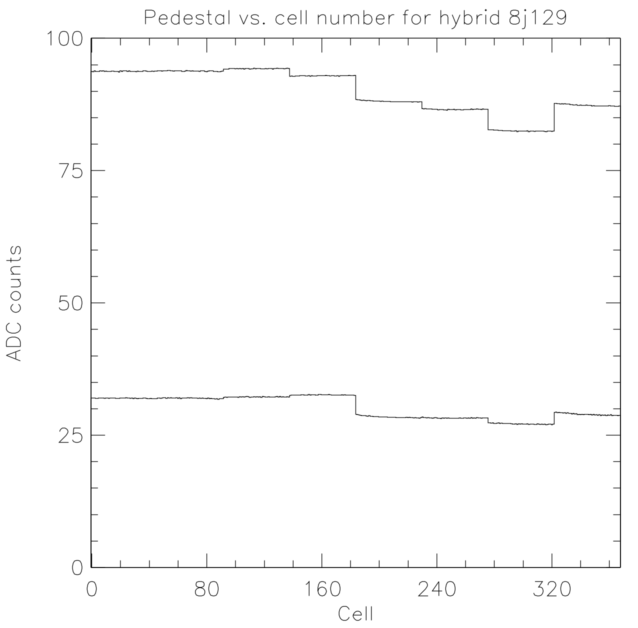
The following plot shows the pedestals vs. channel number with and without charge injection:

Pedestal for each Channel



The following plot shows the average pedestal vs. pipeline cell ID with and without charge injection. The x-axis is cell ID offset by 46 for each chip. Thus cell ID 5 for chip 1 is at x=5, chip 2 at x=51, chip 3 at x=97, etc.

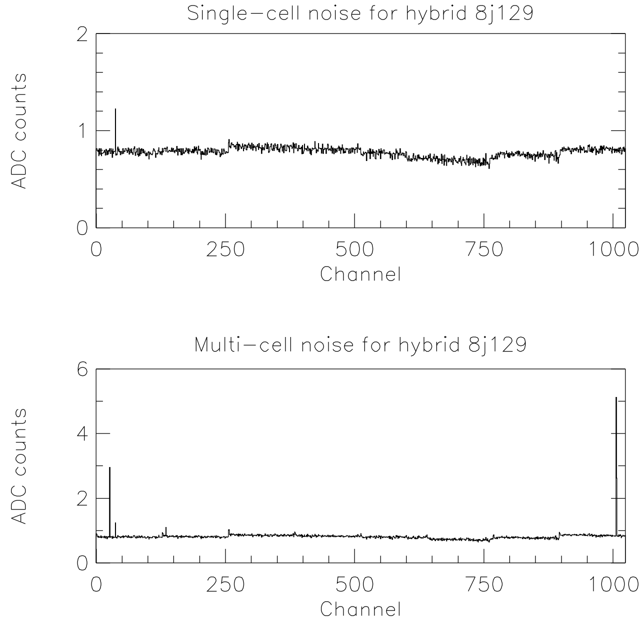
Pedestal vs. Pipeline Cell ID



6 Noise

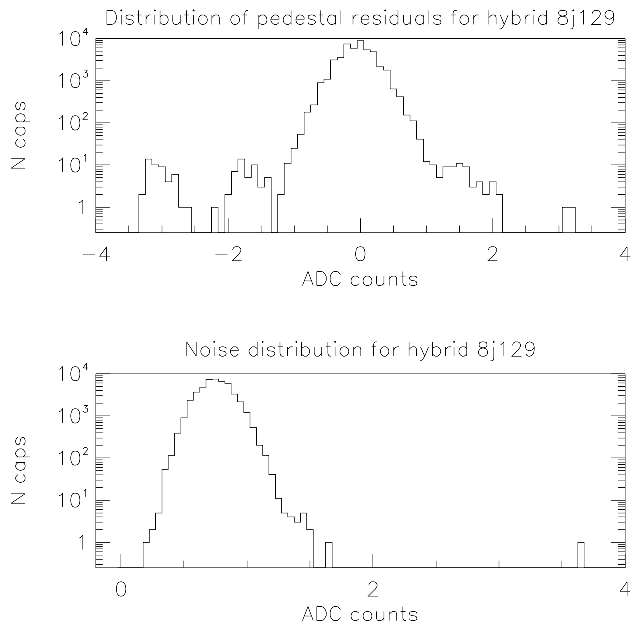
The following plots show the single-cell and multi-cell RMS noise:

RMS Noise



The following are histograms of the pedestal of each pipeline capacitor relative to the chip average (top); and the RMS noise of each capacitor (bottom):

Distribution of Pedestals and Noise



7 Currents

The following plots show the supply currents per chip as a function of measurment number. Currents are measured approximately every 10 minutes:

Supply Currents During Burn-in